



Approved Method **Optical and Electrical
Measurements of AC-LED
Packages and Arrays
or Modules**



**Approved Method: Optical and
Electrical Measurements of AC-LED
Packages and Arrays or Modules**

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Approved by the Standards Committee, February 26, 2018, as a Transaction of the Illuminating Engineering Society.

Approved as an American National Standard Sept. 6, 2018.

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Published by the Illuminating Engineering Society, 120 Wall Street, New York, New York 10005.

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ISBN # 978-0-87995-361-4

Printed in the United States of America.

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Contents

1.0	Introduction and Scope	1
1.1	Introduction	1
1.2	Scope	1
2.0	Normative References	1
2.1	IES LM-85-14	1
2.2	IES RP-16-17	1
3.0	Definitions	1
3.1	AC-LED	1
3.2	AC-LED Package	1
3.3	AC-LED Array Or Module	2
3.4	Device Under Test (Dut)	2
3.5	Remote-Phosphor AC-LED Package	2
3.6	Remote-Phosphor AC-LED Array or Module	2
3.7	Source Measure Unit (SMU)	2
3.8	Temperature-Controlled Mount (TCM)	2
4.0	Optical Measurement Instruments	2
5.0	Electrical Measurement Instruments	2
5.1	Performance of Electrical Measurement Instruments	2
5.	Measurement Uncertainties of Electrical Measurement Instruments	2
6.0	Preparation For Measurements	2
6.1	Seasoning	2
6.2	Operating Orientation	2
6.3	Thermal Conditions	2
6.3.1	Junction Temperature	2
6.3.2	Ambient Air Temperature	3
6.4	Airflow	3
6.5	Humidity	3
7.0	Method Of Measurement Under Single-Cycle AC Operation	3
7.1	General	3
7.2	Measurement Procedure	3
7.3	Estimation of The Measurement Uncertainty	4

8.0	Method Of Measurement Under Continuous AC Operation	5
8.1	General	5
8.2	Measurement Procedure	5
8.3	Methods Used To Determine The Initial Reference Current, $I_f(0)$	7
8.3.1	Rms Initial Reference Current, $I_f(0)_{rms}$	7
8.3.2	Instantaneous Initial Reference Current, $I_f(0)_{ins}$	7
8.4	Estimation of The Measurement Uncertainty Due To Junction Temperature Rise	8
9.0	Optical Measurements	9
10.0	Test Report 1	
10.1	General Information	9
10.2	Description of DUT	9
10.3	Description of Measurement System	9
10.4	Environmental Conditions	10
10.5	Measurement Conditions	10
10.6	Description of Measurement	10
10.7	Optical Quantities (Time-Averaged) (Typical)	10
10.8	Electrical Quantities (Typical)	10
	Additional Reading	10
	Informative References	11